

GigaDevice Semiconductor Inc.

GD30LD3301x 3A High-accuracy, Low Noise LDO

Datasheet

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	- With BIAS: 1.1 V to 6.5 V
	- Without BIAS: 1.4 V to 6.5 V
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	- 0.8 V to 5.2 V, Set by a Resistor Divider
	- 0.8 V to 3.95 V, Pin-Setting, No External Resistor
- Accurate Output Voltage Accuracy: 1%, Over Line, Load and Temperature
- Ultra Low Dropout Voltage: Maximum 180 mV at 3 A with BIAS
- Ultra High PSRR: 39 dB at 500 KHz
- **EXCELLENT Noise Immunity**
	- 5.9 uVRMS at 0.8 V Output
	- 9.8 uVRMS at 5 V Output
- Enable Function
- **Programmable Soft-Start**
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2 Applications

- Wireless Infrastructure: 5G AAU, 4G RRU....
- Telecom/Networking Cards
- Industrial Application

3 General description

The GD30LD3301x is a high-current, low-noise, high accuracy, low-dropout linear regulator (LDO) capable of sourcing 3A with extreme low dropout (max, 180 mV).

The device output voltage is pin-setting from 0.8V to 3.95V and adjustable from 0.8V to 5.2V using the external resistor divider. The device supports input supply voltage as low to 1.1V with BIAS and as low to 1.4V without BIAS.

The low noise, high PSRR and high output current capability makes the GD30LD3301xx ideal to power noise-sensitive devices such as analog-to-digital converters (ADCs), digital-to-analog converters (DACs), and RF components. With very high accuracy, remote sensing, and soft-start capabilities to reduce inrush current, the GD30LD3301x is ideal for powering digital loads such as FPGAs, DSPs, and ASICs.

The external enable control and power good indicator function makes the control sequence easier. The output noise immunity is enhanced by adding external bypass capacitor on

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NR/SS pin. The device is fully specified over the temperature range of TJ = −40°C to 125°C and is offered in a QFN20 3.5x3.5mm package.

4 Device overview

4.1 Block diagram

4.2 Pinout and pin assignment

Figure 4-2 GD30LD3301x QFN20 pinouts

4.3 Pin definitions

Table 4-1. GD30LD3301x QFN20 pin definitions

Notes:

1. Type: $I = input$, $O = output$, $I/O = input$ or output, $P = power$, $G = Ground$.

5 Functional description

5.1 Output Voltage Setting

The output voltage of the GD30LD3301x can be set by external resistors or by using the output voltage setting pins (50mV, 100mV, 200mV, 400mV, 800mV and 1.6V) to achieve different output targets.

By using external resistors, the output voltage is determined by the values of R1 and R2 as shown in Table 7-1. The values of R1 and R2 can be calculated for any voltage value using the following formula:

$$
V_{OUT} = V_{FB} \times \left(1 + \frac{R_1}{R_2}\right)
$$

The GD30LD3301x can also short pins 5, 6, 7, 9, 10, and 11 to ground and program the regulated output voltage level without external resistors after the SNS pin is connected to the Vout. Pins 5, 6, 7, 9, 10, and 11 are connected with internal resistor pairs. Each pin is either connected to ground (active) or left open (floating). Voltage programming is set as the sum of the internal reference voltage (V_{FB} = 0.8V) plus the accumulated sum of the respective voltages assigned to each active pin as illustrated in Table 7-2.

$$
V_{\text{OUT}} = V_{\text{FB}} + V_{\text{PIN-SET}}
$$

5.2 Recommended device selection

5.2.1 CIN and COUT Selection

The GD30LD3301x is designed to support low-series resistance (ESR) ceramic capacitors. It is recommended to use ceramic capacitors with X7R, X5R, and C0G-rated ceramic capacitors to get good capacitive stability across different temperatures.

However, the capacitance of ceramic capacitors varies with operating voltage and temperature, and the design engineer must be aware of these characteristics. Ceramic capacitors are usually recommended to be derated by 50%. A 47μF or greater output ceramic capacitor is suggested to ensure stability. Input capacitance is selected to minimize transient input drop during load current steps. For general applications, an input capacitor of at least 10μF is highly recommended for minimal input impedance. If the trace inductance between the GD30LD3301x input pin and power supply is high, a fast load transient can cause V_{IN} voltage level ringing above the absolute maximum voltage rating which damages the device. Adding more input capacitors is available to restrict the ringing and keep it below the device absolute maximum ratings.

Generally, a 47μF 0805-sized ceramic capacitor in parallel with two 10μF 0805-sized ceramic capacitor ensures the minimum effective capacitance at high input voltage and high

output voltage requirement. Place these capacitors as close to the pins as possible for optimum performance and to ensure stability.

5.2.2 Feed-Forward Capacitor (CFF)

Although a feed-forward capacitor (C_{FF}) from the FB pin to the OUT pin is not required to achieve stability, a 10nF external feed-forward capacitor optimizes the transient, noise, and PSRR performance. A higher capacitance CFF can be used; however, the start-up time is longer and the power-good signal can incorrectly indicate that the output voltage is settled.

5.3 Low-Noise, High-RSRR Output

The GD30LD3301x includes a low-noise reference and error amplifier ensuring minimal noise during operation. The NR/SS capacitor $(C_{NR/SS})$ and feed-forward capacitor (C_{FF}) are the easiest way to reduce device noise. CNR/SS filters the noise from the reference and CFF filters the noise from the error amplifier. The noise contribution from the charge pump is minimal. The overall noise of the system at low output voltages can be reduced by using a bias rail because this rail provides more headroom for internal circuitry.

The high power-supply rejection ratio (PSRR) of the GD30LD3301x ensures minimal coupling of input supply noise to the output. The PSRR performance is primarily results from a high-bandwidth, high-gain error amplifier and an innovative circuit to boost the PSRR between 200kHz and 1MHz.

5.4 Power-Good Function

The PG circuit monitors the voltage at the feedback pin to indicate the status of the output voltage. The PG circuit asserts whenever FB, VIN, or EN are below their thresholds. The PG operation versus the output voltage is shown in Figure 5-1, ch is described by Table 5-1.

Table 5-1 Typical PG Operation Description

The PG pin is open-drain, and connecting a pullup resistor to an external supply enables others devices to receive Power Good as a logic signal that can be used for sequencing. Make sure that the external pullup supply voltage results in a valid logic signal for the receiving device or devices.

To ensure proper operation of the PG circuit, the pullup resistor value must be from 10kΩ and 100kΩ. The lower limit of 10kΩ results from the maximum pulldown strength of the PG transistor, and the upper limit of 100kΩ results from the maximum leakage current at the PG node. If the pullup resistor is outside of this range, then the PG signal may not read a valid digital logic level.

5.5 Soft-Start Function

The GD30LD3301x is designed for a programmable, monotonic soft-start time during the output rising, which can be achieved via an external capacitor (CNR/SS) on NR/SS pin. Using an external C_{NR/SS} is recommended for general application, it is not only for the in-rush current minimization but also helps reduce the noise component from the internal reference. During the monotonic start-up procedure, the error amplifier of the GD30LD3301x tracks the voltage ramp of the external soft-start capacitor $(C_{NR/SS})$ until the voltage approaches the internal reference 0.8V.

The soft-start ramp time can be calculated with equation, which depends on the soft-start charging current (I_{NR/SS}), the soft-start capacitance (C_{NR/SS}), and the internal reference 0.8V (V_{FB}) .

$$
\boldsymbol{t}_{\text{SS}} = \left(\boldsymbol{V}_{\text{NR/SS}} \times \boldsymbol{C}_{\text{NR/SS}}\right) / \boldsymbol{I}_{\text{NR/SS}}
$$

For noise-reduction, CNR/SS in conjunction with an internal noise-reduction resistor forms a low-pass filter (LPF) and filters out the noise from the internal bandgap reference before being amplified via the error amplifier, thus reducing the total device noise floor.

5.6 Undervoltage Lockout (UVLO)

The UVLO circuits ensure that the device stays disabled before its input or bias supplies reach the minimum operational voltage range, and ensures that the device properly shuts down when either the input or bias supply collapses. Figure 5-2 and Table 5-2 explain one of the UVLO circuits being triggered to various input voltage events, assuming $V_{EN} \geq V_{IH(EN)}$.

Figure 5-2 Typical UVLO Operation

Table 5-2 Typical UVLO Operation Description

Similar to many other LDOs with this feature, the UVLO circuits take a few microseconds to fully assert. During this time, a downward line transient below approximately 0.8V causes the UVLO to assert for a short time; however, the UVLO circuits do not have enough stored energy to fully discharge the internal circuits inside of the device. When the UVLO circuits are not given enough time to fully discharge the internal nodes, the outputs are not fully disabled.

The effect of the downward line transient can be mitigated by using a larger input capacitor to increase the fall time of the input supply when operating near the minimum VIN.

5.7 Power Dissipation (P_D)

Circuit reliability demands that proper consideration is given to device power dissipation, location of the circuit on the printed circuit board (PCB), and correct sizing of the thermal plane. The PCB area around the regulator must be as free as possible of other heat-generating devices that cause added thermal stresses.

Power dissipation in the regulator depends on the input-to-output voltage difference and load conditions.

$$
P_{D} = (V_{IN} - V_{OUT}) \times I_{OUT} + V_{IN} \times I_{GND}
$$

 $V_{IN} \times I_{GND}$ represents the static power consumption of the LDO, the value is relatively small and can be ignored. An important note is that power dissipation can be minimized, and thus greater efficiency achieved, by proper selection of the system voltage rails. Proper selection allows the minimum input-to-output voltage differential to be obtained. The low dropout of the device allows for maximum efficiency across a wide range of output voltages.

The main heat conduction path for the device is through the thermal pad on the package. As such, the thermal pad must be soldered to a copper pad area under the device. This pad area contains an array of plated vias that conduct heat to any inner plane areas or to a bottom-side copper plane.

The maximum power dissipation determines the maximum allowable junction temperature (TJ) for the device. Power dissipation and junction temperature are most often related by the j unction-to-ambient thermal resistance $(θ_{JA})$ of the combined PCB, device package, and the temperature of the ambient air (T_A) .

$$
T_{J} = T_{A} + \theta_{JA} \times P_{D}
$$

$$
I_{OUT} = (T_{J} - T_{A}) / \left[\theta_{JA} \times (V_{IN} - V_{OUT})\right]
$$

6 Electrical characteristics

6.1 Absolute maximum ratings

The maximum ratings are the limits to which the device can be subjected without permanently damaging the device. Note that the device is not guaranteed to operate properly at the maximum ratings. Exposure to the absolute maximum rating conditions for extended periods may affect device reliability.

Table 6-1 Absolute maximum ratings

Symbol	Parameter		Max	Unit		
Voltage	IN, BIAS, PG, EN, OUT	-0.3	7.0	V		
	NR/SS, FB	-0.3	3.6	V		
Current	OUT	Internally	Internally	A		
		limited	limited			
	PG(sink current into device)		5	mA		
Thermal characteristics						
TJ	Operating junction temperature		150	°C		
$\mathsf{T}_{\textsf{stg}}$	Storage temperature		150	°C		

6.2 Recommended Operating Conditions

Table 6-2 Recommended Operating Conditions

6.3 Electrical sensitivity

The device is strained in order to determine its performance in terms of electrical sensitivity. Electrostatic discharges (ESD) are applied directly to the pins of the sample.

Symbol	Parameter	Conditions	Value	Unit	
VESD(HBM)	Electrostatic discharge	$T_A = 25 °C$;			
	voltage (human body model)	JS-001-2017	±2000		
$V_{\mathsf{ESD}(\mathsf{CDM})}$	Electrostatic discharge	$T_A = 25 °C$;			
	voltage (charge device model)	JS-002-2018	±500		

Table 6-3 Electrostatic Discharge characteristics

6.4 Electrical Specifications

Over operating temperature range (T_J = -40°C to 125°C), Typical values are at T_J = 25°C. V_{IN} = 1.4 V or V_{IN} = $V_{OUT(TARGE)}$ + 0.4 V, V_{BIAS} = OPEN, $V_{OUT(TARGE)}$ = 0.8 V, V_{OUT} connected to 50 Ω to GND, V_{EN} = 1.1 V, C_{IN} = 10 µF, C_{OUT} = 47 µF, C_{NR/SS} = 0 nF, C_{FF} = 0 nF, and PG pin pulled up to OUT with 100 kΩ, unless otherwise noted.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IN}	Input Range		1.1		6.5	V
V BIAS	BIAS Range	V_{IN} = 1.1 V	3.0		6.5	\vee
V_{FB}	Feedback			0.8		V
	Voltage					
V _{NR/SS}	NR/SS pin			0.8		V
	Voltage					
VUVLO _{1(IN)}	UVLO1 with	V_{IN} rising with $V_{BIAS} = 3.0 V$		0.93	1.085	V
	BIAS					
$V_{HYS1(IN)}$	UVLO1	$V_{BIAS} = 3.0 V$				
	hysteresis With			240		mV

Table 6-4 Electrical characteristics

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} =$ OPEN, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 μF// 10 μF, $C_{\text{NR/SS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 k Ω (unless otherwise noted).

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} = OPEN$, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 µF// 10 µF, $C_{\text{NR/SS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 kΩ (unless otherwise noted).

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} = OPEN$, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 µF// 10 µF, $C_{\text{NRS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 kΩ (unless otherwise noted).

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} = OPEN$, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 µF// 10 µF, $C_{\text{NRS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 kΩ (unless otherwise noted).

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} = OPEN$, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 µF// 10 µF, $C_{\text{NR/SS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 kΩ (unless otherwise noted).

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} = OPEN$, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 µF// 10 µF, $C_{\text{NRS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 kΩ (unless otherwise noted).

 $T_A = 25^{\circ}$ C, $V_{IN} = 1.4$ V or $V_{IN} = V_{OUT(NOM)} + 0.4$ V (whichever is greater), $V_{BIAS} = OPEN$, $V_{\text{OUT(NOM)}} = 0.8$ V, $V_{\text{EN}} = 1.1$ V, $C_{\text{OUT}} = 47$ uF // 10 µF// 10 µF, $C_{\text{NRS}} = 10$ nF, $C_{\text{FF}} = 10$ nF, and PG pin pulled up to V_{IN} with 100 kΩ (unless otherwise noted).

7 Typical application circuit

Figure 7-1 Typical GD30LD3301x application circuit with adjustable resistance

Table 7-1 Adjusted V_{OUT} by external feedback resistor

 $1.8V$ Fixed VOUT (V_{OUT} = V_{FB} + 200mV + 800mV = 1.8V)

Table 7-2 Adjusted Vout by pin-setting

8 Layout guideline

Figure 8-1 Typical GD30LD3301x layout guideline

Notes:

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- 1. The capacitor C_{IN} and C_{OUT} should be placed on the top layer to reduce parasitic parameters.
- 2. All capacitors are as close as possible to the corresponding pins of the LDO.

9 Package information

9.1 QFN20 package outline dimensions

Figure 9-1 QFN20 package outline

Table 9-1. QFN20 dimensions

(Original dimensions are in millimeters)

Figure 9-2 QFN20 recommend footprint

(All dimensions are in millimeters)

9.2 Thermal characteristics

Thermal resistance is used to characterize the thermal performance of the package device, which is represented by the Greek letter "Θ". For semiconductor devices, thermal resistance represents the steady-state temperature rise of the chip junction due to the heat dissipated on the chip surface.

ΘJA: Thermal resistance, junction-to-ambient.

ΘJB: Thermal resistance, junction-to-board.

ΘJC: Thermal resistance, junction-to-case.

ΨJB: Thermal characterization parameter, junction-to-board.

ΨJT: Thermal characterization parameter, junction-to-top center.

 Θ JA = $(T_J - T_A)/P_D$

 Θ JB = $(T_J - T_B)/P_D$

 $\Theta_{\text{JC}} = (T_{\text{J}} - T_{\text{C}})/P_{\text{D}}$

Where, T_J = Junction temperature.

 T_A = Ambient temperature

 T_B = Board temperature

 T_C = Case temperature which is monitoring on package surface

 P_D = Total power dissipation

ΘJA represents the resistance of the heat flows from the heating junction to ambient air. It is an indicator of package heat dissipation capability. Lower Θ_{JA} can be considerate as better overall thermal performance. ΘJA is generally used to estimate junction temperature.

ΘJB is used to measure the heat flow resistance between the chip surface and the PCB board.

ΘJC represents the thermal resistance between the chip surface and the package top case. ΘJC is mainly used to estimate the heat dissipation of the system (using heat sink or other heat dissipation methods outside the device package).

Symbol	Condition	Package	Value	Unit
Θ JA	Natural convection, 2S2P PCB	QFN ₂₀	53.17	°C/W
Θ JB	Cold plate, 2S2P PCB	QFN ₂₀	18.96	°C/W
Θ J $C(Top)$	Cold plate, 2S2P PCB	QFN ₂₀	30.61	°C/W
$\Theta_{\text{JC}(\text{Bottom})}$	Cold plate, 2S2P PCB	QFN ₂₀	7.88	°C/W
Ψ_{JB}	Natural convection, 2S2P PCB	QFN ₂₀	19.14	°C/W
Ψ_{JT}	Natural convection, 2S2P PCB	QFN ₂₀	2.56	°C/W

Table 9-2. Package thermal characteristics(1)

(1) Thermal characteristics are based on simulation, and meet JEDEC specification.

10 Ordering information

Table 10-1 Part ordering code for GD30LD3301x devices

11 Revision history

Table 11-1 Revision history

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